Approval Sheet

Customer	
Product Number	**M0SB-56PA4W03-J**
Module speed	**PC-133**
Pin	**144 Pin**
CAS Latency	**CL-3**
Operating Temp	**-40C~85C**
Date	**3rd April 2014**

Approval by Customer

P/N:

Signature:

Date:

Sales: **Sr. Technical Manager: John Hsieh**

Rev 1.0

1. Features

Key Parameter

Industry Nomenclature	Speed Grade	Data Rate MT/s			tRCD (ns)	tRP (ns)	tRC (ns)
		CL=2	CL=2.5	CL=3			
PC-133	B	100	-	133-	20	20	65

- Single Pulsed /RAS interface
- Fully Synchronous to positive CLK edge
- 4 banks controlled by BA0 & BA1
- Multiple Burst Read with single write option
- Automatic and controlled precharge command
- Auto refresh (CBR) and Self-Refresh
- JEDEC Standard 144-pin Memory Module
- Intend for 133 MHz applications
- Inputs and Outputs are LVTTL compatible
- VDD=VDDQ= 3.3 Volt ± 0.3
- Serial Presence Detect with EEPROM
- Operation Temperature *(Note 1)*
  - Wide Temperature (–40°C ≤ T_A ≤ +85°C)
- Programmable Device Operation:
  - Burst Type: Sequential or Interleave
  - Device CAS# Latency: 2 and 3
  - Burst Length: 1, 2, 4 or 8
- RoHS Compliant *(Section 14)*

2. Environmental Requirements

iDIMM are intended for use in standard office environments that have limited capacity for heating and air conditioning.

Symbol	Parameter	Rating	Units	Notes
T_{OPR}	Operating Temperature (ambient)	-40 to +85	°C	1
T_{STG}	Storage Temperature	-55 to +125	°C	

1. The refresh rate is required to double when T_C exceeds 85°C.

3. Ordering Information

W/T SDR SODIMM						
Part Number	Density	Speed	Organization	Number of DRAM	Number of rank	ECC
M0SB-56PA4W03-J	256MB	PC-133	16Mx16	8	2	N

4. Pin Configurations (Front side/Back side)

Pin	Front	Pin	Back	Pin	Front	Pin	Back	Pin	Front	Pin	Back
1	V_{SS}	2	V_{SS}	51	DQM14	52	DQM46	95	DQ21	96	DQ53
3	DQ0	4	DQ32	53	DQM15	54	DQM47	97	DQ22	98	DQ54
5	DQ1	6	DQ33	55	V_{SS}	56	V_{SS}	99	DQ23	100	DQ55
7	DQ2	8	DQ34	57	NC	58	NC	101	V_{DD}	102	V_{DD}
9	DQ3	10	DQ35	59	NC	60	NC	103	A6	104	A7
11	V_{DD}	12	V_{DD}	Voltage Key				105	A8	106	BA0
13	DQ4	14	DQ36					107	V_{SS}	108	VSS
15	DQ5	16	DQ37					109	A9	110	BA1
17	DQ6	18	DQ38	61	**CLK0	62	**CKE0	111	A10/AP	112	A11
19	DQ7	20	DQ39	63	V_{DD}	64	V_{DD}	113	V_{DD}	114	V_{DD}
21	V_{SS}	22	V_{SS}	65	$\overline{RAS}$	66	$\overline{CAS}$	115	DQM2	116	DQM6
23	DQM0	24	DQM4	67	$\overline{WE}$	68	**CKE1	117	DQM3	118	DQM7
25	DQM1	26	DQM5	69	**$\overline{CS0}$	70	A12	119	V_{SS}	120	V_{SS}
27	V_{DD}	28	V_{DD}	71	**$\overline{CS1}$	72	*A13	121	DQ24	122	DQ56
29	A0	30	A3	73	DU	74	**CLK1	123	DQ25	124	DQ57
31	A1	32	A4	75	V_{SS}	76	V_{SS}	125	DQ26	126	DQ58
33	A2	34	A5	77	NC	78	NC	127	DQ27	128	DQ59
35	V_{SS}	36	V_{SS}	79	NC	80	NC	129	V_{DD}	130	V_{DD}
37	DQ8	38	DQ40	81	V_{DD}	82	V_{DD}	131	DQ28	132	DQ60
39	DQ9	40	DQ41	83	DQ16	84	DQ48	133	DQ29	134	DQ61
41	DQ10	42	DQ42	85	DQ17	86	DQ49	135	DQ30	136	DQ62
43	DQ11	44	DQ43	87	DQ18	88	DQ50	137	DQ31	138	DQ63
45	V_{DD}	46	V_{DD}	89	DQ19	90	DQ51	139	V_{SS}	140	V_{SS}
47	DQ12	48	DQ44	91	V_{SS}	92	V_{SS}	141	SDA	142	SCL
49	DQ13	50	DQ45	93	DQ20	94	DQ52	143	V_{DD}	144	V_{DD}

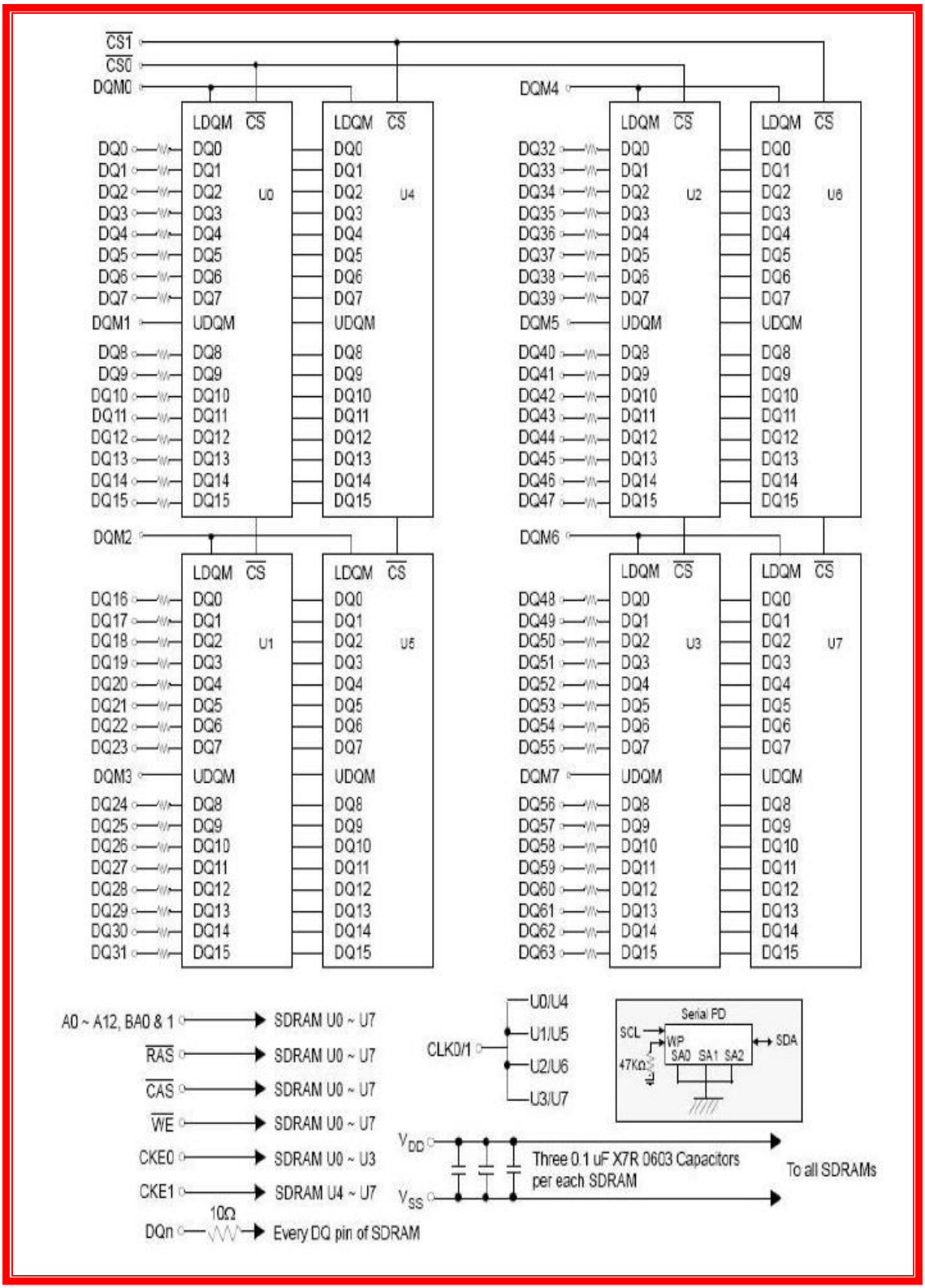
5. Architecture

Pin Definition

Pin Name	Description	Pin Name	Description
A0 - A12	SDRAM address bus	CKE0 – CKE1	SDRAM clock enable lines
BA0 - BA1	SDRAM Bank Address Inputs	SCL	Serial Presence Detect Clock Input
/RAS	SDRAM row address strobe	SDA	Serial Presence Detect Data input/output
/CAS	SDRAM column address strobe	DQM0 – DQM7	SDRAM data masks
/WE	SDRAM write enable	V_{DD}	Power Supply
/CS0 - /CS1	Chip select input	V_{SS}	Ground
CLK0 – CLK1	SDRAM Clock input.	DU	Spare Pin
DQ0 – DQ63	DIMM memory data bus	NC	No connection

6. Function Block Diagram:

- (256MB, 2 Rank, 16Mx16 SDR SDRAMs)



7. Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
T_{STG}	Storage Temperature	-55 to 125	°C
V_{INPUT}	Voltage input pins relative to Vss	-1.0 to +4.6	V
V_{DD}	Voltage on VDD supply relative to Vss	-1.0 to +4.6	V
V_{DDQ}	Voltage on VDDQ supply relative to Vss	-1.0 to +4.6	V

Note: Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is stress rating only, and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

8. DC Operating Conditions

- DC Electrical Operating Conditions

(T_A =-40 °C ~ 85 °C; V_{SS} = 0V)

Symbol	Parameter	Min	Typ.	Max	Units	Notes
VDD	Supply Voltage	3.0	3.3	3.6	V	1
VDDQ	Supply Voltage	3.0	3.3	3.6	V	1
VIH (DC)	Input High (Logic1) Voltage	2.0	-	VCC + 0.3	V	1,2
VIL (DC)	Input Low (Logic0) Voltage	-0.5	-	0.8	V	1,3

Note:

1. All voltages referenced to Vss and VssQ
2. **VIH (max) = VDD** + 1.2V for pulse width ≤ 5ns.
3. **VIL (min) = VSS** +-1.2V for pulse width ≤ 5ns.

- DC Electrical Characteristics

(T_A = -40 °C ~ 85 °C; V_{SS} = 0V)

Symbol	Parameter	Min	Max	Units
II(L)	Input Leakage Current, any input (0.0V ≤ VIN ≤ VDD), All Other Pins Not Under Test = 0V	-10	+10	µA
IO(L)	Output Leakage Current (DOUT is disabled, 0.0V ≤ VOUT ≤ VDDQ)	-10	+10	µA
VOH	Output Level (LVTTL) Output “H” Level Voltage (IOUT = -2.0mA)	2.4	-	V
VOL	Output Level (LVTTL) Output “L” Level Voltage (IOUT = +2.0mA)	-	0.4	V

9. Capacitance

(T_A = -40 ℃ ~ 85 ℃; V_{DD} = 3.3±0.3V)

Symbol	Parameter	Max	Units
C_{I1}	Input Capacitance (A0 to A11, /RAS,/CAS, /WE)	40	pF
C_{I2}	Input Capacitance (/CS0, /CSI)	25	pF
C_{ICL}	Input Capacitance (CLK0-CLK1)	28	pF
C_{I3}	Input Capacitance (CKE0, CKEI)	20	pF
C_{I4}	Input Capacitance (DQ0-DQ7)	10	pF
C_{SC}	Input Capacitance (SCL, SA0-2)	8	pF
C_{IO}	Input/Output Capacitance	18	pF

10. Operating, Standby, and Refresh Currents

- 256MB SODIMM (2 Rank, 16Mx16 SDR SDRAMs T_A = -40 °C ~ 85 °C; V_{DDQ} = V_{DD} = 3.3V ± 0.2V)

Symbol	Parameter/Condition		PC-133	Unit
I_{CC1}	Operation Current: Burst length = 4, CL = 3, t_{RC}> = t_{RC}(min), t_{CK}> = t_{CK}(min), IO = 0 mA, 2 Bank Interleave Operation		760	mA
I_{CC2P}	Precharged Standby Current in Power Down Mode: CKE< = V_{IL}(max), t_{CK}> = t_{CK}(min)		16	mA
I_{CC2N}	Precharged Standby Current in Non-Power Down Mode: CKE> = V_{IH}(min), t_{CK}> = t_{CK}(min), Input changed once in 3 cycles.		240	mA
I_{CC3N}	Active Standby Current in Non-Power Down Mode: CKE> = V_{IH}(min), t_{CK}> = t_{CK}(min), Input changed one time		240	mA
I_{CC3P}	Active Standby Current in Power Down Mode: CKE< = V_{IL}(max), t_{CK}> = t_{CK}(min)		40	mA
I_{CC4}	Burst Operating Current: Burst length = Full Page, t_{RC} = Infinite, CL = 3, t_{CK}> = t_{CK}(min), IO = 0 mA 2 Banks Activated		720	mA
I_{CC5}	Auto Refresh Current: t_{RC}>= t_{RC}(min)		1600	mA
I_{CC6}	Self Refresh Current: CKE = <0.2 V	Standard	16	mA
		L-Version	9.6	

1. Currents given are valid for a single device. .
2. These parameters depend on the cycle rate and are measured with the cycle determined by the minimum value of t_{CK} and t_{RC}. Input signals are changed up to three times during t_{RC}(min).
3. The specified values are obtained with the output open.
4. Input signals are changed once during t_{CK}(min).
5. Input signals are changed once during three clock cycles.
6. Active Standby Current will be higher if Clock Suspend is entered during a burst read cycle (add 1mA per DQ).
7. Input signals are stable.

11. AC Timing Specifications

(T_A =-40 °C ~ 85 °C; V_{DDQ} = V_{DD} , See AC Characteristics)

Symbol	Parameter	PC-133		Unit
		Min.	Max.	
Clock and Clock Enable				
tAC	DQ output access time from CK/CK#	-	5.4	ns
tCH	CK high-level width	2.5	-	ns
tCL	CK low-level width	2.5	-	ns
fCK	System frequency	100	133	MHz
tCK	Clock Cycle Time	7.5	10	ns
tCS	input setup time	1.5	-	ns
tCH	input hold time	0.8	-	ns
tCKSP	CKE Setup Time (Power down mode)	2	-	ns
tCKSR	CKE Setup Time (Self Refresh Exit)	8	-	ns
tT	Transition time (rise and fall)	1	-	ns
Command Parameters				
tRCD	/RAS to /CAS delay	20	-	ns
tRC	Cycle Time	60	-	ns
tRAS	Active command Period	45	100K	ns
tRP	Precharge Time	20	-	ns
tRRD	Bank to Bank delay time	15	-	ns
tCCD	/CAS to /CAS delay time (same bank)	1	-	CLK
Refresh Cycle				
tSREX	Self Refresh Exit Time	10	-	ns
tREF	Refresh Period (8192 cycles)	64	-	ms

Symbol	Parameter	PC-133		Unit
		Min.	Max.	
Read Cycle				
t_{OH}	Data Out Hold Time	3	-	ns
t_{LZ}	Data Out to Low Impedance Time	0	-	Ns
t_{HZ}	Data Out to High Impedance Time	3	7.5	ns
t_{DQZ}	DQM Data Out Disable Latency	2	-	CLK
Write Cycle				
t_{DPL}	Data input to Precharge (write recovery)	1	-	CLK
t_{DAL}	Data In to Active/refresh	5	-	CLK
t_{DQW}	DQM Write Mask Latency	0	-	CLK

12. SPD

Serial Presence Detect – (256MB)

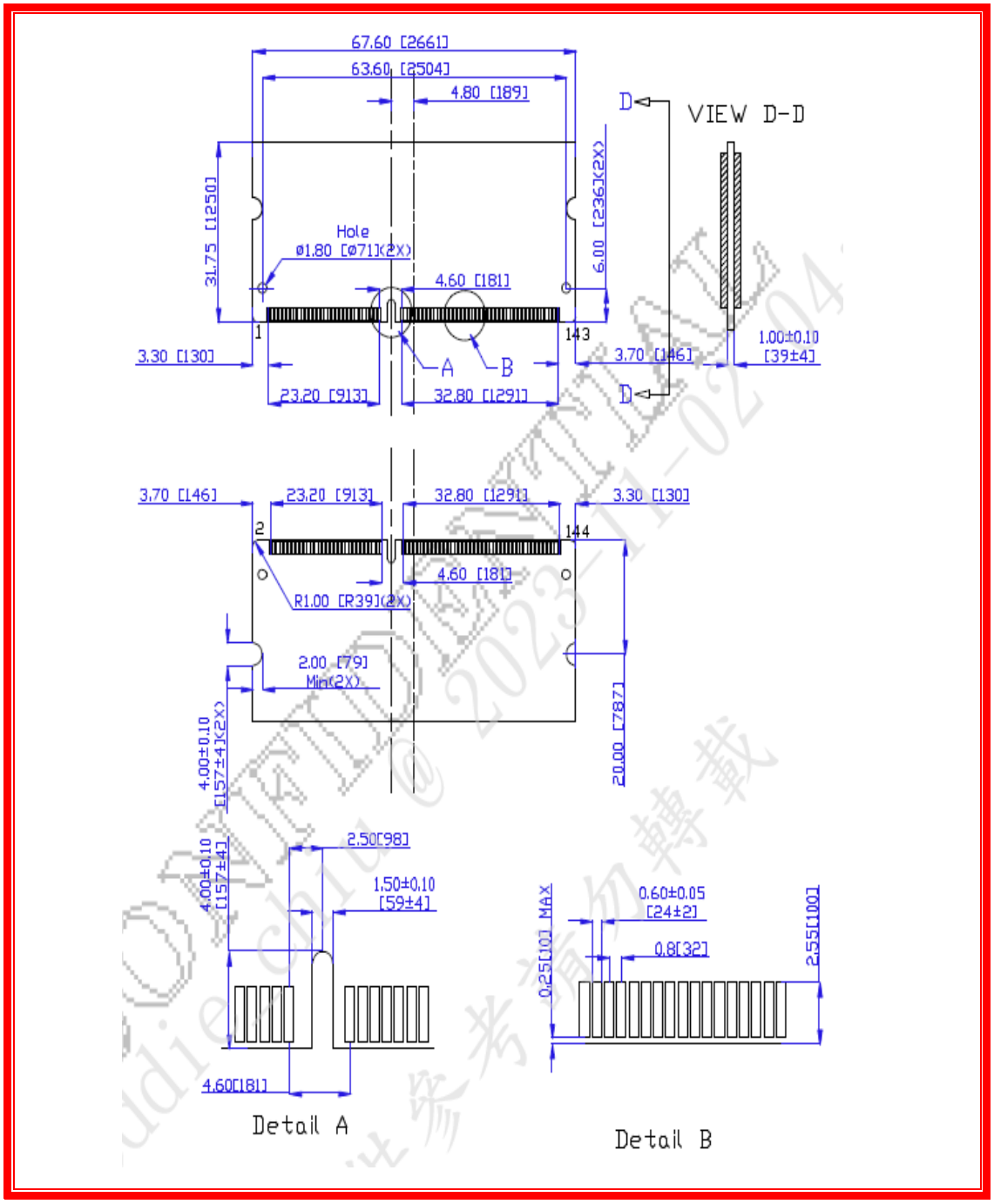
16Mx64 2 RANK UNBUFFERED SDRAM DIMM based on 16Mx16, 4Banks, 8K Refresh, 3.3V with SPD

Byte	Description	Serial PD Data Entry (Hexadecimal)		Note
0	Number of Serial PD Bytes Written during Production	80		
1	Total Number of Bytes in Serial PD device	08		
2	Fundamental Memory Type	04		
3	Number of Row Addresses on Assembly	0D		
4	Number of Column Addresses on Assembly	09		
5	Number of DIMM Bank, Package, and Height	02		
6	Data Width of this Assembly	40		
7	Reserved	00		
8	Voltage Interface Level of this Assembly	01		
9	DDR2 SDRAM Cycle Time at CL=5 (ns)	75		
10	DDR2 SDRAM Access Time from Clock at CL=5 (ns)	54		
11	DIMM Configuration Type	00		
12	Refresh Rate/Type	82		
13	Primary DDR2 SDRAM Width	10		
14	Error Checking DDR2 SDRAM Device Width	00		
15	Minimum Clock Delay from Back to Back Random Column Address	01		
16	Burst Length Supported	8F		
17	Number of Device Banks	04		
18	/CAS Latencies Supported	06		
19	/CS Latencies	01		
20	/WE Latencies	01		
21	SDRAM Module Attributes:	00		

Byte	Description	Serial PD Data Entry (Hexadecimal)	Note
22	SDRAM Device Attributes: General	0E	
23	Minimum Clock Cycle at CL=2	A0	
24	Maximum Data Access Time (t_{ac}) from Clock at CL=2	60	
25	Minimum Clock Cycle Time at CL=1	00	
26	Maximum Data Access Time (t_{ac}) from Clock at CL=1	00	
27	Minimum Row Precharge Time (t_{RP})	14	
28	Minimum Row Active to Row Active delay (t_{RRD})	0F	
29	Minimum RAS to CAS delay (t_{RCD})	14	
30	Minimum RAS Pulse Width (t_{RAS})	2D	
31	Module Bank Density	20	
32	SDRAM Input Setup Time	15	
33	SDRAM Input Hold Time	08	
34	Data Input Setup Time Before Clock (t_{DS})	15	
35	Data Input Hold Time After Clock (t_{DH}) (ns)	08	
36-48	Superset Information (May be used in Future)	00	
49	Reserve	00	
50-61	Reserve	00	
62	SPD Revision	02	
63	Checksum for Bytes 0 - 62	AA	
64-71	Manufacture's JEDEC ID Code	**7F 7F 7F 7F 7F 7F F1 FF**	
72	Module Manufacturing Location	**02**	
73-91	Module Part number	**69 2D 44 49 4D 4D 4D FF FF FF FF FF FF FF FF FF FF FF FF 00**	
92-255	Reserved	**-**	

13. PACKAGE DIMENSION

- (256M, 2 Ranks, 16Mx16 SDR SDRAMs)



Note: Device position is only for reference.

14. RoHS Declaration

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Declaration of Conformity

We, InnoDisk Co., Ltd, here declare the product M0SB-56PA4W03/-(X) complies with the requirement of RoHS directives 2006/12/EC

Innodisk ensures the above product meets RoHS requirements of six restricted substances. This declaration is based on vendor supplied analysis/MSDS, material certifications, and/ or 3rd party test reports of the component/ raw materials used in the manufacture of products.

Name of hazardous substance	Limited of RoHS ppm（mg/kg）
Cd	< 100 ppm
Pb	< 1000 ppm
Hg	< 1000 ppm
Chromium VI（Cr+6）	< 1000 ppm
Polybromodiphenyl ether（PBDE）	< 1000 ppm
Polybrominated Biphenyls（PBB）	< 1000 ppm

Date issued: 2013/07/23

Manufacturer: ：InnoDisk Co., Ltd.
Address：9F, No. 100, Sec.1 Xintai 5th Rd., Xizhi City, Taipei 221, Taiwan

Authorized Signature：

QA Dept. Director – Ryan Tsai

Revision Log

Rev	Date	Modification
0.1	3rd April 2014	Preliminary Edition
1.0	3rd April 2014	Official Release.